

HNS50N65F/P/T (HN65R190)

650V N-Channel Enhancement Mode MOSFET

Description

The HNS50N65F/P/T is **CoolFET II** MOSFET family that is utilizing charge balance technology for extremely low on-resistance and low gate charge performance.

HNS14N65F/P/T is suitable for applications which require superior power density and outstanding efficiency

General Features

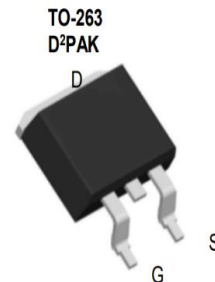
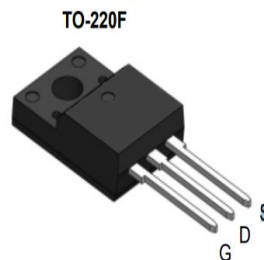
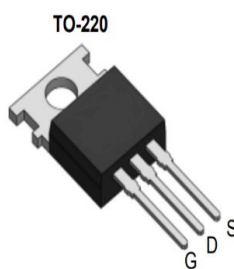
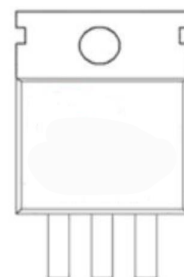
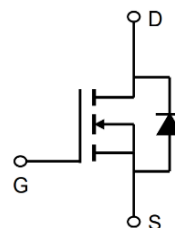
$V_{DS} = 650V$ (Type: 740V) $IDM = 50A$

$R_{DS(ON)} < 190m\Omega$ @ $V_{GS}=10V$ (Type: 150m Ω)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
HNS50N65F	TO-220F-3L	HNS50N65F XXX YYYY	1000
HNS50N65P	TO-220-3L	HNS50N65P XXX YYYY	1000
HNS50N65T	TO-263-3L	HNS50N65T XXX YYYY	1000

Absolute Maximum Ratings ($T_c=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DS}	Drain-Source Voltage ($V_{GS} = 0V$)	650	V
I_D	Continuous Drain Current	21	A
I_{DM}	Pulsed Drain Current (note1)	50	A
V_{GS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note2)	500	mJ
P_D	Power Dissipation ($T_c = 25^{\circ}C$)	151	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^{\circ}C$
R_{thJC}	Thermal Resistance, Junction-to-Case	0.82	$^{\circ}C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	62	$^{\circ}C/W$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain to source breakdown voltage	V _{GS} =0V, I _D =250uA	650	740	--	V
ΔBV _{DSS} / ΔT _J	Breakdown voltage temperature coefficient	I _D =250uA, referenced to 25°C	--	0.7	--	V/°C
IDSS	Drain to source leakage current	V _{DS} =650V, V _{GS} =0V	--	--	1	uA
		V _{DS} =520V, T _C =125°C	--	--	50	uA
IGSS	Gate to source leakage current, forward	V _{GS} =30V, V _{DS} =0V	--	--	100	nA
	Gate to source leakage current, reverse	V _{GS} =-30V, V _{DS} =0V	--	--	-100	nA
VGS(TH)	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250uA	2.5	3.3	4.5	V
RDS(ON)	Drain to source on state resistance	V _{GS} =10V, I _D =3.2A	--	150	190	mΩ
Ciss	Input capacitance	V _{GS} =0V, V _{DS} =100V, f=1MHz	--	1510	--	pF
Coss	Output capacitance		--	65	--	
Crss	Reverse transfer capacitance		--	2.4	--	
td(on)	Turn on delay time	V _{DS} =400V, I _D =13A, R _G =4.7Ω, V _{GS} =13V	--	10	--	ns
tr	Rising time		--	19.8	--	
td(off)	Turn off delay time		--	45.4	--	
tf	Fall time		--	41.4	--	
Qg	Total gate charge	V _{DS} =480V, V _{GS} =10V, I _D =11A	--	7.27	--	nC
Qgs	Gate-source charge		--	17.4	--	
Qgd	Gate-drain charge		--	43.9	--	
IS	Continuous source current	Integral reverse p-n Junction diode in the MOSFET	--	--	21	A
ISM	Pulsed source current		--	--	63	A
VSD	Diode forward voltage drop.	I _S =7.3A, V _{GS} =0V	--	0.812	1.5	V
Trr	Reverse recovery time	I _S =11A, V _{GS} =0V, V _{DD} =400V, di/dt=100A/us,	--	288	--	ns
Qrr	Reverse recovery Charge		--	3.66	--	uC

Note :

- 1、The data tested by surface mounted on a 1 inch2 FR-4 board with 20Z copper.
- 2、The EAS data shows Max. rating . L=0.5mH, IAS =7A, VDD =50V, RG=25Ω
- 3、The test condition is Pulse Test: ISD ≤ ID, di/dt = 100A/us, VDD≤ BVDSS, Starting at TJ =25°C
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

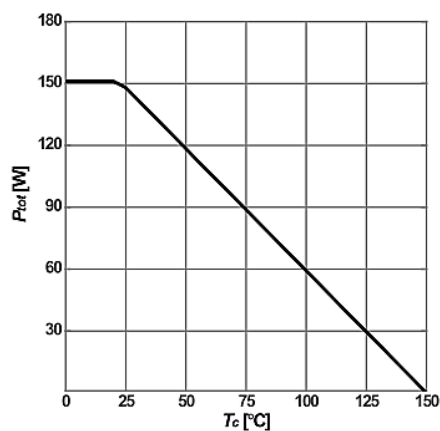


Figure1: Power dissipation (Non FullPAK)

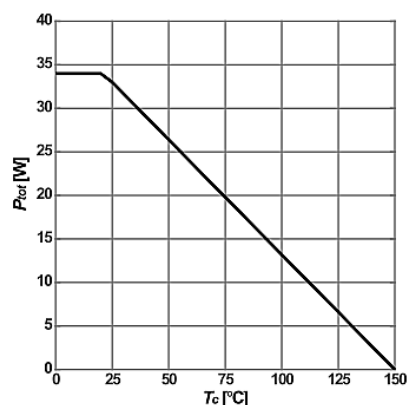


Figure2: Power dissipation (FullPAK)

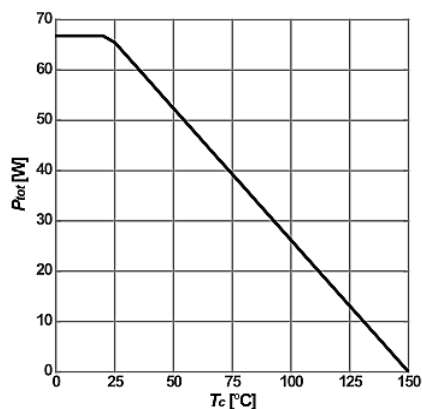


Figure3: Power dissipation

$$P_{tot}=f(T_c)$$

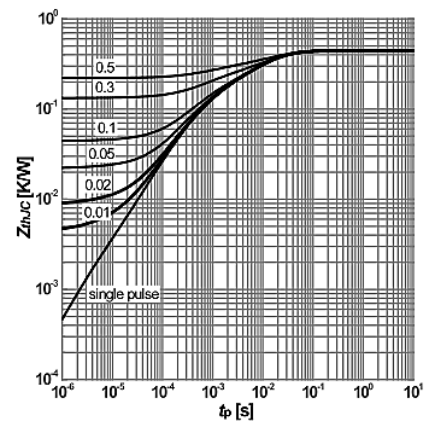


Figure4: Max. transient thermal impedance

$$Z_{thJC}=f(t_p); \text{ parameter: } D= t_p/T$$

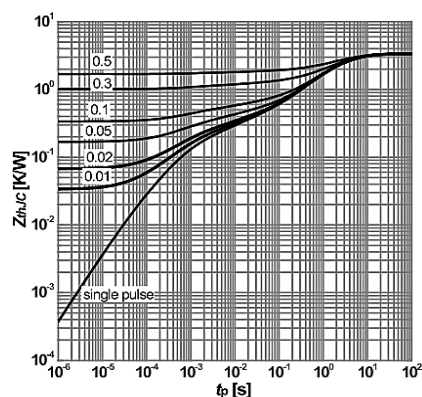


Figure5: Max. transient thermal impedance

$$Z_{thJC}=f(t_p); \text{ parameter: } D= t_p/T$$

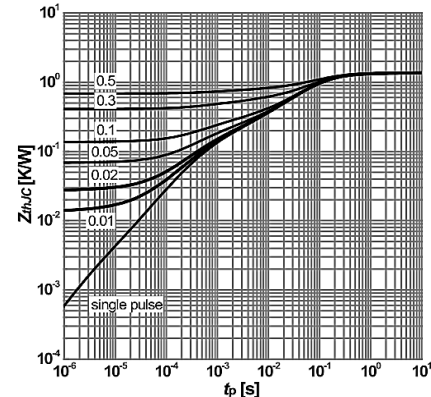


Figure6: Max. transient thermal impedance

$$Z_{thJC}=f(t_p); \text{ parameter: } D= t_p/T$$

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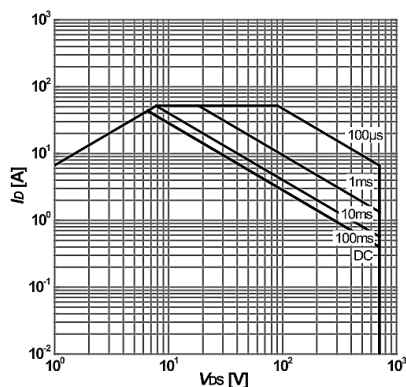


Figure 7: Safe operating area (Non FullPAK)

$I_D = f(V_{DS})$; $T_J = 25^\circ\text{C}$; $D = 0$; parameter: t_p

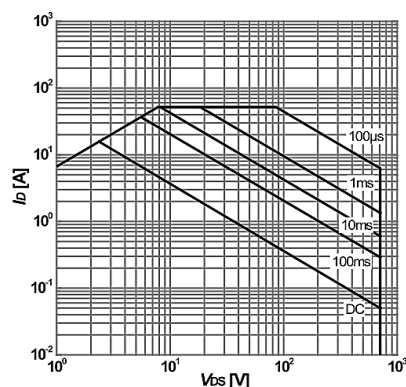


Figure 8: Safe operating area (Non FullPAK)

$I_D = f(V_{DS})$; $T_J = 25^\circ\text{C}$; $D = 0$; parameter: t_p

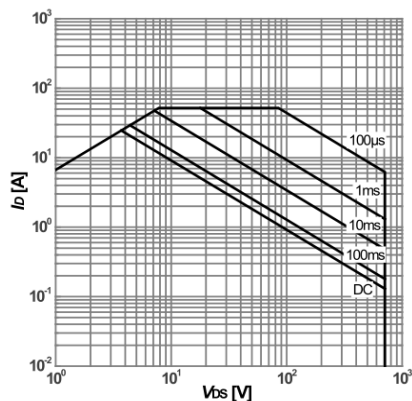


Figure 9: TSafe operating area (FullPAK-TO220A)

$R_{DS(on)} = f(I_D)$; $T_J = 25^\circ\text{C}$; parameter: V_{GS}

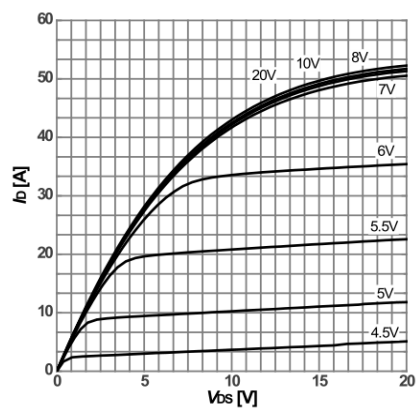


Figure 10: Typ. output characteristics

$R_{DS(on)} = f(T_J)$; $I_D = 3.2\text{A}$; $V_{GS} = 10\text{V}$

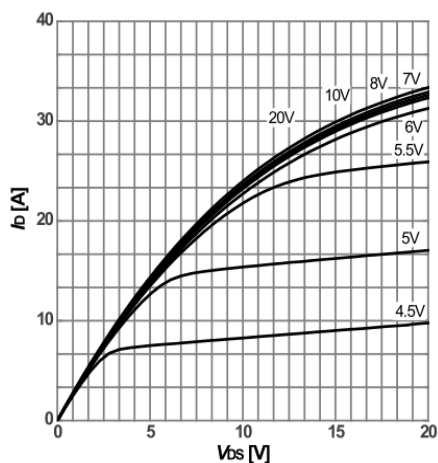


Figure 11: Typ. output characteristics

$I_D = f(V_{DS})$; $T_J = 125^\circ\text{C}$; parameter: V_{GS}

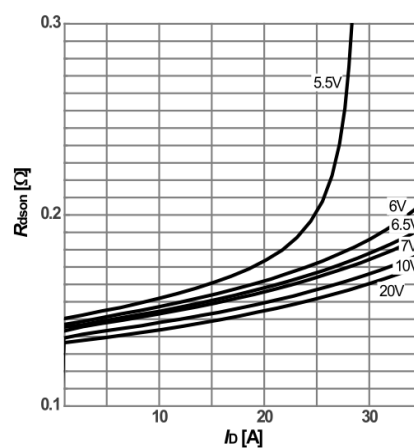


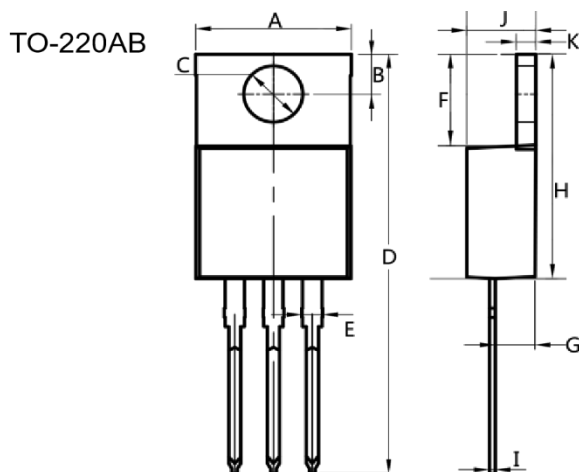
Figure 12: Type. gate charge

$R_{DS(on)} = f(I_D)$; $T_J = 25^\circ\text{C}$; parameter: V_{GS}

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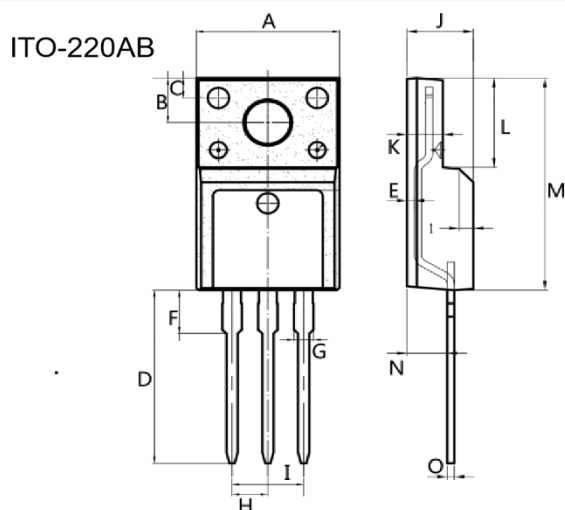
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Package Mechanical Data-TO-X



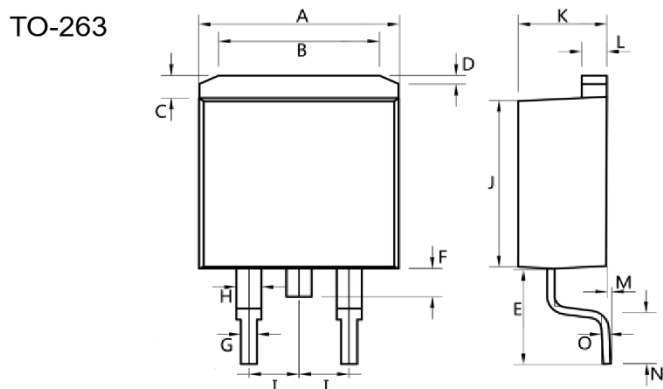
Dim.	Min.	Max.
A	10.0	10.4
B	2.5	3.0
C	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
H	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4

All Dimensions in millimeter



Dim.	Min.	Max.
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	Typ 2.54	
I	Typ 5.08	
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

All Dimensions in millimeter



Dim.	Min.	Max.
A	10.0	10.5
B	7.25	7.75
C	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
H	1.15	1.35
I	Typ 2.54	
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
M	0.02	0.1
N	2.4	2.8
O	0.35	0.45

All Dimensions in millimeter